Form PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. 30-5004 DIV3

PRIORITY SERIAL NO. 09/465,492

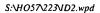
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)

APPLICANT Vladimir Segal et al.

PRIORITY FILING DATE December 16, 1999 PRIORITY GROUP 1742

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			·	U.S. PATENT DOCUMENTS				
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing If Appr	Date .
HW	AA	4,619,695	10/1986	Oikawa et al.	75	65EB		
HW	AB	5,400,633	03/1995	Segal et al.	72	272		
HW	AC	5,513,512	05/1996	Segal	72	253.1		
HW	AD	5,590,389	12/1996	Dunlop et al.	419	67		
HW	AE	5,600,989	02/1997	Segal et al.	72	253.1		
HW	AF	5,673,581	10/1997	Setal	72	184		
HW	AG	4,663,120	05/1987	Parent et al.	-			
HW	АН	4,762,558	08/1988	German et al.				
HW	AI	4,889,745	12/1989	Sata				
MM	AJ	5,330,701	07/1994	Shaw et al.	-			
MW	AK	5,418,071	05/1995	Satou et al.				
HW	- 		04/1996	Satou et al.				_
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MW	AM	590904	04/1994	EP	C23C	14/34		
NW	AN AO	9201080 610107	01/1992	PCT Japan (*transl. of Abst)	C23C	14/35	2/4	
#W	AP	693400	1		C22	18	X*	
AW			04/1994	Japan (*transl. of Abst)	C22	18	X*	
NV	AQ	6256919 OTH	09/1994 ER REFERENC	Japan (*transl. of Abst) ES (including Author, Title, Date, Pertinent Pages, E	C22	18	X*	
1.4	AR	C. Klein et al., "	Manual of Minera	alogy", pp 39-40				
AW	,		<u>-</u>		·		· -	
10 1	AS	S. Wright et al. "		ng Temperature on the Texture of Rolled Tantalum	and Tantulu	m-10 Wi.% To	ungstun, repri	inted from
HW		Tungsten and Re	fractory Metals 2,	pp 501-508				
10 /	AT	H-R Wenk, "Pref	erred Orientation	in Deformed Metals and Rocks: An Introduction to	Modern Tex	ture Analysis",	, 1985, pp 8-	10
KW					<u></u>			
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AW	AA	5,608,911		03/1997	Shaw et al.					1			
MW	АВ	5,772,860		08/1998	Sawada et al.					ů	9)		
X	AC	5,993,621		11/1999	Liu					•			
Z	AD	5,798,005		08/1998	Murata et al.					,			
MM	AE	5,282,946		02/1994	Kinoshita et al.				-	-			
AW	AF	5,993,575		11/1999	Lo et al.				-				
HW	AG	5,809,393		08/1998	Dunlop et al.					,			
MW	АН	5,468,401	468,401		Lum et al.	um et al.				•			
MW	Al	5,087,297		02/1992	Pouliquen					,			
pw	AJ	5,693,203		12/1997	Ohhashi et al.					,			
MG	AK	5,074,907		12/1991	Amato et al.					_			
MK	AL	4,525,417		06/1985	Dimigen et al.					٦			
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AW	AM	8-100255		04/1996	Japan					,	X	- No	
HW	AN	8-64554		03/1996	Japan					-	Х	ļ	
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TM /	AR	B.D.	Cullity, "Stru	cture of Polycrys	talline Aggregates", Elements o	of >	X-ray Diffraction, pp	294-297					
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APPLICANT Vladimir Segal et al.

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,	AA	SN 09/098,760 As filed and Amended		Shah et al.				6/17/98	
MM	AB	4,842,706	06/1989	Fukasawa et al.		_			
MW	AC	4,960,163	10/1990	Fang et al.					
WW	AD	5,780,755	07/1998	Dunlop et al.					
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1714	AA	5,850,755 RAD	12/98	Segal						
MW	АВ	5,456,815	10/95	Fukuyo et al.					_	
LAW	AC	5,826,456	10/98	Kawazoe et al.	_		<u> </u>			
HW	AD	5,413,650	5/95	Jarrett et al.			-			
LAW	AE	6,193,821 B1	2/01	Zhang						
HW	AF	6,348,113 B1	2/02	Michaluk et al.						
12W	AG	6,085,966	7/00	Shimomuki et al.						
HW	АН	6,024,852	2/00	Tamura et al.				_		
14W	AI	5,798,005	08/98	Murata et al.				-		
HW	AJ	5,231,306	07/93	Meikle et al.				<u> </u>		
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,		Document	Date	Country	· Y	Class	Subclass	Transl	ation	
		Number						Yes	No	
MW	AM	WO 99/66100	23.12.1999	PCT						
HW	AN	WO 87/07650	17.12.1987	PCT						
MM	AO	0 882 813 A1	09.12.1998	EPO			├ ──			
11V	AP	08146201	07.06.1996	Japan		-				
Mid	AQ	10008244	13.01.1998							
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AW	AR	Mukai et al., "Dyn: 765, NanoStructure		Properties of a Near-Nano Alumi 10, No. 5	num Alloy Processed I	oy Equal-Cha	nnel-Abular-Ex	atrusion", -1998	, pp. 755	
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111.7	AS	Ferrasse, S. et al., Mater. Res. Vol. 1	Ferrasse, S. et al., "Development of a Submicrometer-Grained Microstructure in Aluminum 6061 Using Equal Channel Angular Extr. Mater. Res. Vol. 12, No. 5, May 1997, pp. 1253-1261.						usion", J.	
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HW	AT	Ferrasse, S. et al., Extrusion", Metallu	Ferrasse, S. et al., "Microstructure and Properties of Copper and Aluminum Alloy 3003 Heavily Worked by Equal Channel Angular Extrusion", Metallurgical and Materials Transactions A, vol. 28A, April 1997, pp. 1047-1057.							
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WW	AR	Pavate et al., "Cor SPIE Vol. 3214, 19	relation between 1997, pp. 42-47.	Aluminum alloy sputtering target	metallurgical characte	ristics, Arc init	iation, and I	n-film defect-c	lensity",	
W. I	AS	Hatch, J.E., ALUN 183.	<u>иіпим</u> , 1984, Сі	nap. 5, "Metallurgy of Heat Treatr	nent and General Pri	nciples of Preci	pitation Hea	iting", pp. 134-	157, 175-	
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